

AMENDMENTS TO THE SPECIFICATION:

Kindly replace the paragraph beginning on page 6, line 11, with the following amendment paragraph.

Fig. 1 is the schematic constitution diagram showing the scan test system for a semiconductor device according to Embodiment 1 of the present invention. Fig. 1 shows a semiconductor mounted board 1 such as printed circuit board, a semiconductor device 2 (first semiconductor device), an analog sensor 3 (second internal circuit, second semiconductor device), a scan register 4, an analog input/output pin 5, a digital input/output pin 6, an analog wiring 7, input/output pin 26 and an internal system logic 8 (first internal circuit).